Notice of References Cited 10/735,501 Reexamination ONISHI ET AL. Examiner Matthew E Warren 2815 Reexamination ONISHI ET AL. Page 1 of 1

Application/Control No.

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,724,042	04-2004	Onishi et al.	257/341
	В	US-6,677,626	01-2004	Shindou et al.	257/266
	ပ	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	1.	US-			
	J	US-			
	κ	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2001332726 A	11-2001	Japan	INOUE et al.	H01L 29/78
	0					
	Р				·	
	ď					
	R					·
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	υ							
	V							
	w							
	х							

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Applicant(s)/Patent Under